OIPE 4	Region of the second of the se		
noi .	FORM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. ESDI.PAU.02	SERIAL NO. : 10/635,390
STENT & TRADE	LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT  (USE SEVERAL SHEETS IF NECESSARY)	APPLICANT(S): Rodov et al.	
		FILING DATE: August 6, 2003	GROUP: 2818

## Reference Designation

## U.S. PATENTS AND PUBLISHED APPLICATIONS

Examiner Initial	Document Number	Date	Name	Class	Filing Date Subclass if appropriate	
UH	6,259,139	07/10/2001	Pan	Class	арргориас	
100	6,436,744	08/20/2002	Bryant et al.			
	6,353,236	03/05/2002	Yatsuo et al.			
	6,734,093	05/11/2004	Sabin et al.			
	2002/0070424	06/13/2002	Uenishi	\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-\-	<del></del>	
· <b>V</b>	2002/00/0424	00/13/2002	Ochishi			
	<del> </del>					
	<u> </u>				<del> </del>	
<del></del>						
<del></del>						
	ļ					
	<del> </del>					
	<del></del>					
	<u> </u>	<del></del>	• •			
	-					
<del></del> -	<del> </del>		-			
·····						
<del></del>						
	<del> </del>					
•		FOREIGN PAT	ENT DOCUMENTS	_		
					Filing Date	
					Subclass if	
	Document Number	Date	Country	Class	appropriate	
	OTHER ART (INCLU	DING AUTHOR; TIT	LE, DATE, PERTINENT P	AGES, ETC.)		
		<del></del> -		<del></del>	***************************************	
			•			
EXAMINE	<u> </u>		DATE	CONSIDERED		
EXAMINE	Mailuo	18,05	DATE		100	
	1 HVVarmor			10/22/	04_	

1	PRM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. ESD1.PAU.02	SERIAL NO. : 10/635,390
<u> </u>	LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT  (USE SEVERAL SHEETS IF NECESSARY)	APPLICANT(S): Rodov et al.	
İ		FILING DATE: August 6, 2003	GROUP: 2818

Reference Designation

U.S. PATENTS

Examiner					Filing Date Subclass if	
Initial	Document Number	Date	Name	Class	арргоргіате	
7/2/	6,153,913	11/28/2000	Hsu et al.			
11.18	5,537,284	07/16/1996	Haas, Jr. et al.			
ATTO	6,157,530	12/05/2000	Pequignot et al.			
	6,268,286	07/31/2001	Gauthier, Jr. et al.			
<del>Wa -</del>	6,034,388	03/07/2000	Brown et al.			
11:11	6,331,726	12/18/2001	Voldman			
1700	5,689,133	11/18/1997	Li et al.			
MAL	6,292,343	09/18/2001	Pequignot et al.			
74/19		07/17/2001	Pequignot et al.	<del></del>		
MIK	6,262,873	0//1//2001	requignot et al.			
		-	<del></del>			
•		FOREIGN PAT	ENT DOCUMENTS	IT DOCUMENTS		
					Filing Date Subclass if	
	Document Number	Date	Country	Class	appropriate	
	OTHER ART (INCLU	DING AUTHOR, TIT	LE, DATE, PERTINENT PA	AGES, ETC.)		
MA	Test Structures for Benchmi Sematech, Inc., February 27		Discharge (ESD) Robustne	ss of CMOS Tecl	nologies,	
NH	Characterization, Modeling, and Design of ESD Protection Circuits, Stephen G. Beebe, Advanced Micro Devices, March 1998					
	Investigation of ESD Perfor	mance in Advanced C	MOS Technology, A dissert	ation Submitted t	o the	
MU	Fulfillment of the Requirem	Department of Electrical Engineering and the Committee on Graduate Studies of Stanford University in Partial Fulfillment of the Requirements for the Degree of Doctor of Philosophy, Kwang-Hoon Oh, October 2002				
WH	Lighting Rods for Nanoelec October 2002	tronics, Steven H. Vol	dman, Scientific American,	Vol. 287, No. 4, F	gs. 90-97,	
EXAMINE	R		DATEC	CONSIDERED	777	
	1111011111	LOND	0	7/01/	UL	